In place of U. S. DEPARTMENT OF COMMERCE PTO-1449 PATENT AND TRADEMARK OFFICE Form		Complete if Known			
				Application Number	Not Yet Known
INFORMATION DISCLOSURE STATEMENT BY APPLICANT			SURE	Filing Date	December 2, 2004
			CANT	Applicant(s)	Johan Torsner, et al.
(use as many sheets as necessary)			sary)	Art Unit	Not Yet Known 2611
				Examiner Name	NOT YOLKHOWN NURUL MATIN
SHEET	1	OF	1	Attomey Docket Number	P16904-US1

U. S. PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document	
/NM/	AA	2003007490 A1	01/09/2003	YI, S.J. et al	
			 		
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FOREIGN PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date	Patentee or Applicant of Cited Document	Translation YAN
/NM/	AB	EP 1278293 A2	01/15/2003	LG Electronics Inc	
/NM/	AC	WO 0156249 A1	08/02/2001	Telefonaktiebolaget LM Ericsson (publ)	
/NM/	AD	JP 2001 83860 A	06/30/2000	Fujitsu Ltd	
		 	 		

OTHER PRIOR ART					
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume issue number(s), publisher, city/country where published			
/NM/	AE	SA DA COSTA, C. ET AL, Sequence synchronization in the ATM adaption layer, Proceedings of the Mediterranean Electrotechnical Conference, 1991, 22-24 May 1991, pages 505-508, vol. 1. page 505, column 3, line 1, page 507, column 2, line 26			
/NM/	AF	Patent Abstracts of Japan, vol. 2000, no 09, October 12, 2000			
/NM/	AG	Swedish patent Office, International Search Report for PCT/SE/03/00868, dated August 19, 2003.			

Examiner Signature	/Nurul Matin/	Date Considered	06/01/2007
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

10/516716 12 Rec'd PCT/PTO 0 2 DEC 2004

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				Examiner Name	Not Yet Known Nurul Matin
SHEET	1	OF	1	Attorney Docket Number	P16904-US1

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/NM/	AF	Patent Abstracts of Japan, vol. 2000, no 09, October 12, 2000			
/NM/	AG	Swedish patent Office, International Search Report for PCT/SE/03/00866, dated August 19, 2003.			

l Examiner	1	Date	
	/Nicosi Matin/	Date	11
Signature	/Nurul Matin/	Considered	06/01/2007
Signature	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	Considered	06/01/2007

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